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 APPLICANT
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GROUP

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U.S. PATENT DOCUMENTS

Examiner Initials	U.S. Patent Document		Name of Patentee or Applicant of Cited Document	Date of Publication (MM-DD-YYYY)
	Number	Kind Code (if known)		
AC	5,510,230		Tennant et al.	04-23-1996
AC	5,512,759		Sweatt	04-30-1996
AC	5,920,380		Sweatt	07-06-1999
AC	6,033,079		Hudyma	03-07-2000
AC	6,072,852		Hudyma	06-06-2000
AC	6,084,938		Hara et al.	07-04-2000
AC	6,183,095		Hudyma	02-06-2001
AC	6,188,513		Hudyma	02-13-2001
AC	6,198,793		Schultz et al.	03-06-2001
AC	6,226,346		Hudyma	05-01-2001
AC	6,262,836		Hudyma et al.	07-17-2001

FOREIGN PATENT DOCUMENTS

Examiner Initials	Foreign Patent Document		Country	Date of Publication (MM-DD-YYYY)	Translation	
	Number	Kind Code (if known)			Yes	no
	NONE					

NON PATENT LITERATURE DOCUMENTS

Examiner Initials	Include name of author (in CAPITAL LETTERS), title of the article (when appropriate), title of the item (book, magazine, journal, serial, symposium, catalog, etc.), date, page(s), volume-issue number(s), publisher, city and/or country where published.		
AC	Naulleau, P. et al., "Characterization of the accuracy of EUV phase-shifting point diffraction interferometry", <i>SPIE</i> , vol. 3331, pp. 114-123		
AC	White, D.L. et al., "Modification of the coherence of undulator radiation", <i>Rev. Sci. Instrum.</i> , 66 (2), Feb. 1995, pp. 1930-1933		
Examiner Signature	Amel C. Linares	Date Considered	10/18/02

EXAMINER: Initial if reference considered, whether or not citation is in conformance with MPEP 609; draw line through citation if not in conformance and not considered. Include copy of this form with next communication to applicant. SEND TO: Assistant Commissioner for Patents, Washington, D.C. 20231.